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Optics and photonics — Measurement of reflectance of plane surfaces and transmittance of plane parallel elements

Optique et photonique — Mesurage du facteur de réflexion des surfaces planes et du facteur de transmission des éléments à plan parallèle



ISO 15368:2021(E)

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Foreword

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This document was prepared by Technical Committee ISO/TC 172, *Optics and photonics*, Subcommittee SC 1, *Fundamental standards*.

This second edition cancels and replaces the first edition ISO 15368:2001 which has been technically revised. The main changes compared to the previous edition are as follows:

- Throughout the document, descriptions of the use of Fourier transform spectrometer instruments have been expanded and added where appropriate to an equivalent level as those of monochromator instruments.
- Throughout the document, the term "light" has been replaced with "optical radiation" to reflect that this standard's spectral range extends beyond the visible.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

Introduction

Measurements of reflectance and transmittance using spectrophotometers are the most fundamental methods for the characterization of optical components. Since the spectrophotometric methods are basic and normal, they are extensively used and provide measurement data over a wide range of wavelengths.

This document describes the measurement of reflectance and transmittance using spectrophotometers, which provides data with high reproducibility and repeatability.